

SEMICONDUCTOR®

#### October 2013

# FQP4N20L N-Channel QFET<sup>®</sup> MOSFET 200 V, 3.8 A, 1.35 Ω

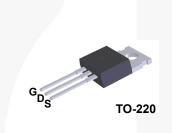
# Description

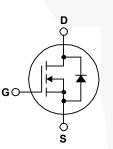
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology. This advanced technology is especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation modes. These devices are well suited for high efficiency switching DC/DC converters, switch mode power supplies, and motor control.

## Features

• 3.8 A, 200 V, R\_{DS(on)} = 1.35  $\Omega$  (Max.) @ V\_{GS} = 10 V, I\_D = 1.9 A

- Low Gate Charge (Typ. 4.0 nC)
- Low Crss (Typ. 6.0 pF)
- 100% Avalanche Tested





### Absolute Maximum Ratings T<sub>c</sub> = 25°C unless otherwise noted.

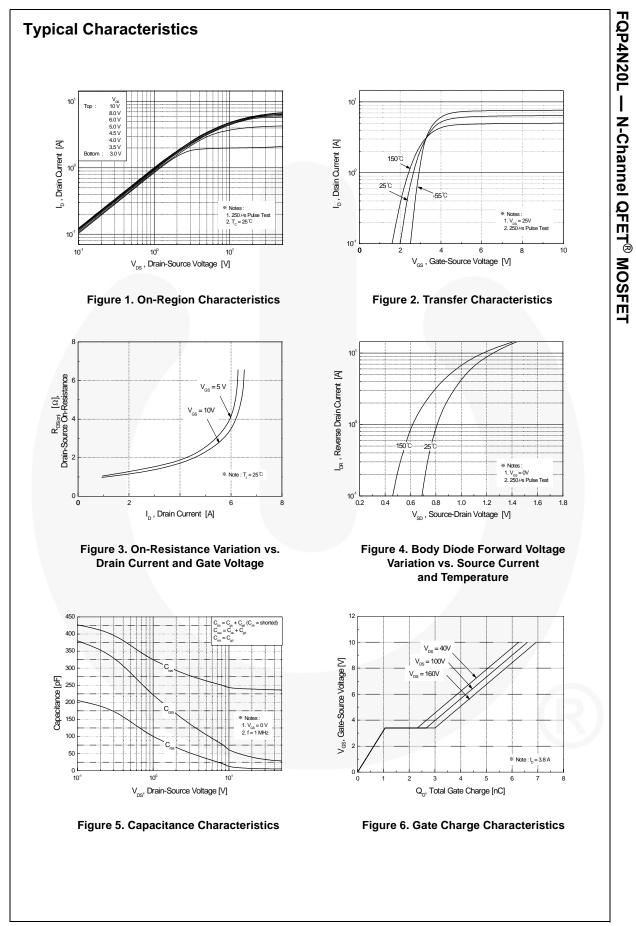
Symbol	Parameter Drain-Source Voltage		FQP4N20L	Unit V	
V <sub>DSS</sub>			200		
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°	3.8	А		
	- Continuous (T <sub>C</sub> = 100	2.4	A		
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	15.2	A	
V <sub>GSS</sub>	Gate-Source Voltage		± 20	V	
E <sub>AS</sub>	Single Pulsed Avalanche Energy	(Note 2)	52	mJ	
I <sub>AR</sub>	Avalanche Current	(Note 1)	3.8	A mJ	
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	4.5		
dv/dt	Peak Diode Recovery dv/dt (Note 3)		5.5	V/ns	
P <sub>D</sub>	Power Dissipation ( $T_C = 25^{\circ}C$ )	45	W		
	- Derate above 25°C		0.36	W/°C	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C	
TL	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C	

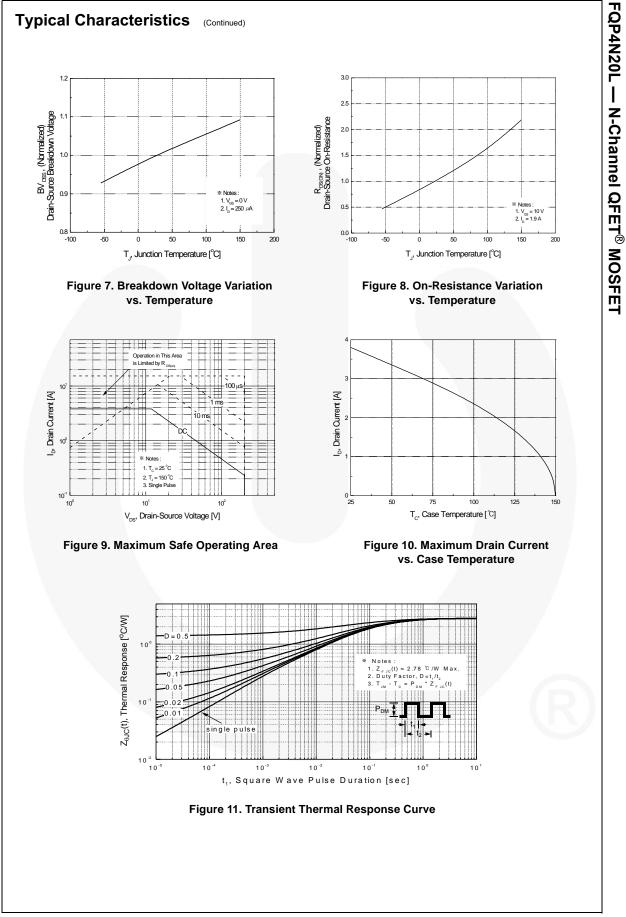
### **Thermal Characteristics**

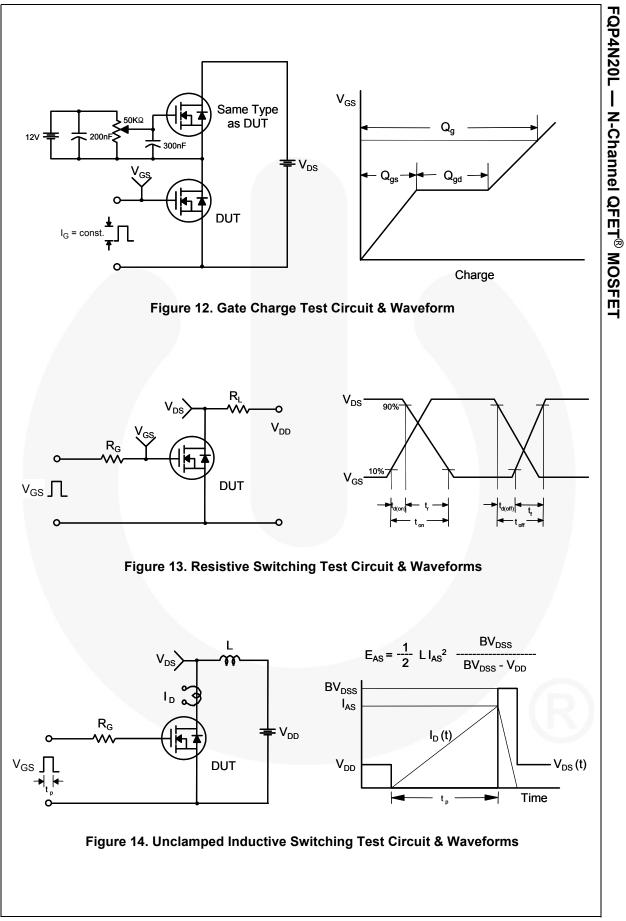
Symbol	Parameter	FQP4N20L	Unit °C/W	
$R_{ extsf{ heta}JC}$	Thermal Resistance, Junction-to-Case, Max.	2.78		
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink, Typ.	0.5	°C/W	
$R_{\thetaJA}$	Thermal Resistance, Junction-to-Ambient, Max.	62.5	°C/W	

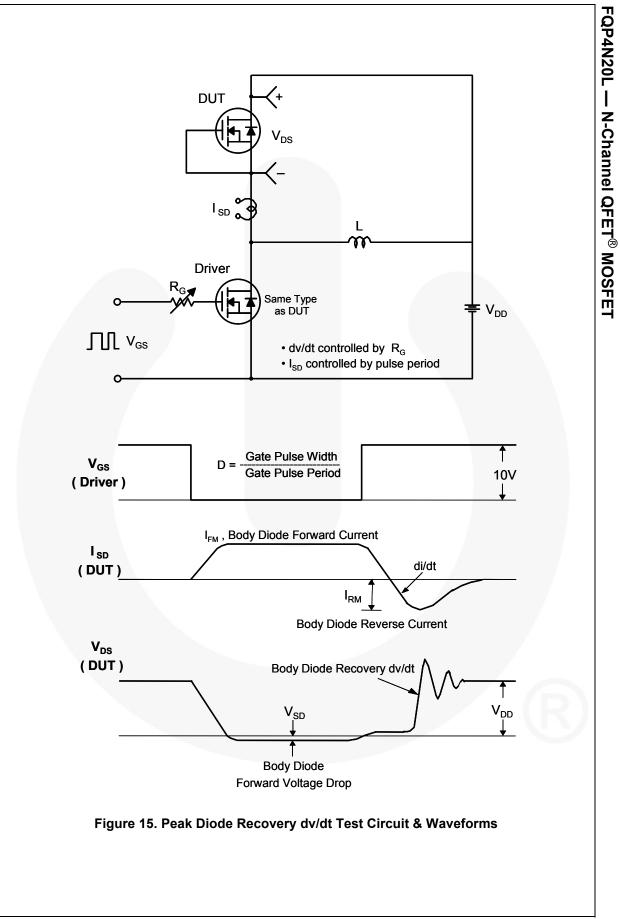
Part Nu	mber	ber Top Mark	Package	Packing Method	Reel	Size	Tape W	idth	Quantity	
FQP4N	120L			0-220 Tube N		A	N/A		50 units	
lectri	cal Ch	naracteristics <b>r</b>	<sub>c</sub> = 25°C unless oth	erwise noted.						
Symbol		Parameter		Test Conditions		Min	Тур	Max	Unit	
	rector	otion								
BV <sub>DSS</sub>	Drain-S		ane Vos	<sub>s</sub> = 0 V, I <sub>D</sub> = 250 μA		200			V	
ABV <sub>DSS</sub>	Drain-Source Breakdown Voltage					200			· ·	
$\Delta T_{J}$		Breakdown Voltage Temperature Coefficient		$I_D = 250 \ \mu$ A, Referenced to 25°C			0.16		V/°C	
DSS	Zero Gate Voltage Drain Current		V <sub>DS</sub>	$V_{DS} = 200 \text{ V}, V_{GS} = 0 \text{ V}$ $V_{DS} = 160 \text{ V}, T_{C} = 125^{\circ}\text{C}$				1	μA	
			nt V <sub>DS</sub>					10	μA	
GSSF	Gate-B	Gate-Body Leakage Current, Forward		$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$				100	nA	
GSSR		ody Leakage Current, F		s = -20 V, V <sub>DS</sub> = 0 V				-100	nA	
On Cha	racteri	stics								
V <sub>GS(th)</sub>		nreshold Voltage	V <sub>DS</sub>	= V <sub>GS</sub> , I <sub>D</sub> = 250 μA		1.0		2.0	V	
R <sub>DS(on)</sub>	Static D	)rain-Source	-	$= 10 \text{ V}, \text{ I}_{\text{D}} = 1.9 \text{ A}$			1.10	1.35		
20(01)	On-Res	sistance	V <sub>GS</sub>	= 5 V, I <sub>D</sub> = 1.9 A			1.13	1.40	Ω	
9 <sub>FS</sub>	Forward	d Transconductance	V <sub>DS</sub>	= 25 V, I <sub>D</sub> = 1.9 A			3.2		S	
	1	acteristics								
C <sub>iss</sub>		apacitance	V <sub>DS</sub>	$V_{DS} = 25 V, V_{GS} = 0 V,$			240	310	pF	
C <sub>oss</sub>		Capacitance		I.0 MHz			36	45	pF	
C <sub>rss</sub>	Revers	e Transfer Capacitance					6	8	pF	
Switchi	ing Cha	aracteristics								
d(on)	Turn-O	n Delay Time	Van	V <sub>DD</sub> = 100 V, I <sub>D</sub> = 3.8 A,			7	25	ns	
t <sub>r</sub>	Turn-O	n Rise Time		$= 25 \Omega$			70	150	ns	
d(off)	Turn-Of	ff Delay Time					15	40	ns	
f	Turn-Of	ff Fall Time			(Note 4)		40	90	ns	
ე <sup>g</sup>	Total G	ate Charge	V <sub>DS</sub>	= 160 V, I <sub>D</sub> = 3.8 A,			4.0	5.2	nC	
Q <sub>gs</sub>	Gate-S	ource Charge		s = 5 V			1.0		nC	
ე <sub>gd</sub>	Gate-D	rain Charge		(Note			1.9		nC	
Drain-S	ource	Diode Characteris	stics and M	aximum Ratings						
S	1	Im Continuous Drain-S						3.8	Α	
SM	Maximum Pulsed Drain-Source Diode Forward Current				15.2	А				
/ <sub>SD</sub>		ource Diode Forward V		s = 0 V, I <sub>S</sub> = 3.8 A			)	1.5	V	
rr	Revers	e Recovery Time	V <sub>GS</sub>	$V_{GS} = 0 V, I_S = 3.8 A,$			90		ns	
2 <sub>rr</sub>	Reverse	e Recovery Charge	00	/ dt = 100 A/μs			0.25		μC	
. L = 5.4 mH	, I <sub>AS</sub> = 3.8 A, di/dt ≤ 300 /	e-width limited by maximum jur V <sub>DD</sub> = 50 V, R <sub>G</sub> = 25 Ω, starti A/µs, V <sub>DD</sub> ≤ BV <sub>DSS</sub> , starting T <sub>J</sub> =	ng T <sub>J</sub> = 25°C.						0	

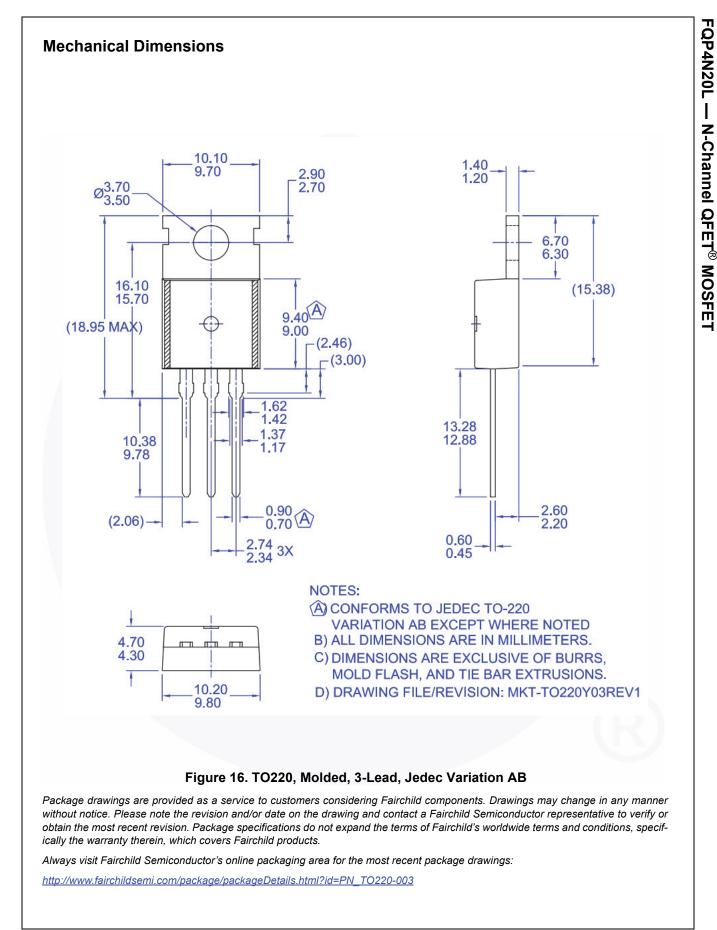
FQP4N20L — N-Channel QFET<sup>®</sup> MOSFET













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